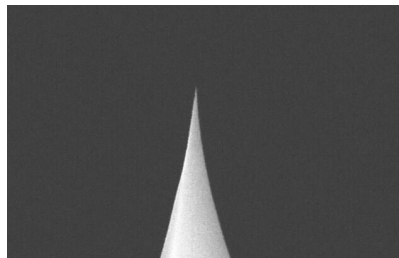


SHOCON-SS

SHOCON-SS probes are Super-Sharp silicon probes designed for contact mode applications. These probes feature shorter cantilevers, which provide better sensitivity without compromising on spring constant requirements. Our Super Sharp probes yield enhanced resolution images.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** >3.5
- **ROC (nm) :** 2
- **Coating:** None



SHOCON-SS

On click zoom images

[Download Spec](#)

Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex coating : None

Parameter	Nominal	Min	Max
k (N/m)	0.14	0.01	0.60
f (kHz)	21.0	8.0	37.0
Length (μm)	225.0	215.0	235.0
Width (μm)	46.0	41.0	51.0
Thickness (μm)	1.00	0.50	1.50